## Notice of References Cited

Application/Control No. 10/804,406	Reexamination	Applicant(s)/Patent Under Reexamination LEE, TAE WON		
Examiner	Art Unit			
Paulos M. Natnael	2622	Page 1 of 1		

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,034,893	04-2006	Liu et al.	348/614
*	В	US-6,950,477	09-2005	Meehan et al.	375/267
*	С	US-6,111,542	08-2000	Day et al.	342/359
*	D	US-5,771,015	06-1998	Kirtman et al.	342/359
*	Е	US-5,748,226	05-1998	Limberg, Allen LeRoy	348/21
*	F	US-5,995,135	11-1999	Limberg, Allen Leroy	348/21
*	G	US-5,835,131	11-1998	Limberg, Allen L.	348/21
*	Н	US-5,801,759	09-1998	Limberg, Allen L.R.	348/21
*	l	US-6,005,894	12-1999	Kumar, Derek D.	375/270
*	J	US-6,351,500	02-2002	Kumar, Derek D.	375/270
*	Κ	US-7,006,040	02-2006	Henderson et al.	342/372
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## NON-PATENT DOCUMENTS

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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